



5/9/2009

RELIABILITY MONITOR REPORT
FOR

Chartered 0.35 μ m Silicon Gate CMOS

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

This Report was prepared by
Maxim Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

DS26303	DS33R11
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The calculated failure rate for devices using this process is:

FAILURE RATE: **MTTF (YRS): 19388** **FITS: 5.9**

The parameters used to calculate this failure rate are as follows:

Cf: 60% **Ea: 0.7** **Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 1/1/2008 and 12/31/2008.

Process Information:

Process Description: Chartered 0.35µm Silicon Gate CMOS

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	0811	DS26303	125C, 3.5 VOLTS	1000 HRS	45	0	QN080344BB-NPI
HIGH TEMP OP LIFE	0812	DS33R11	125C, 3.5V (PSA) & 2.0V (PSB)	1000 HRS	60	0	QK080847AC
HIGH TEMP OP LIFE	0816	DS33R11	125C, 3.5V (PSA) & 2.0V (PSB)	1000 HRS	60	0	QK080847AD
Total:						0	

STORAGE LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
STORAGE LIFE	0812	DS33R11	150C	1000 HRS	77	0	QK080847AC
STORAGE LIFE	0816	DS33R11	150C	1000 HRS	77	0	QK080847AD
Total:						0	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	0812	DS33R11	-55C TO 125C	1000 CYS	77	0	QK080847AC
TEMP CYCLE, 5' RAMP, 10' DWELL	0816	DS33R11	-55C TO 125C	1000 CYS	77	0	QK080847AD
Total:						0	

TEMPERATURE HUMIDITY BIAS

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
BIASED MOISTURE	0812	DS33R11	85/85, 3.5 VOLTS	1000 HRS	45	0	QK080847AC

